

N-Channel Enhancement Mode Power MOSFET

Description

The HM180N02K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

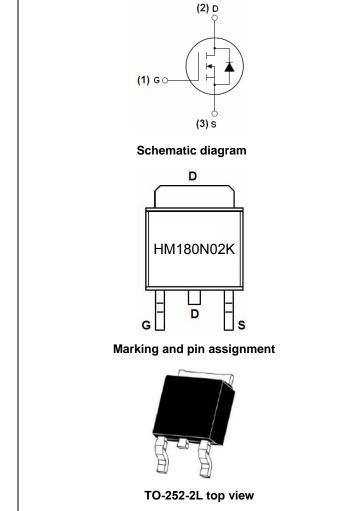
- $V_{DS} = 20V, I_D = 185A$ $R_{DS(ON)} < 2.0 \text{ m}\Omega @ V_{GS} = 4.5V$ $R_{DS(ON)} < 2.4 \text{m}\Omega @ V_{GS} = 2.5V$
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

100% UIS TESTED!

100% ΔVds TESTED!



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM180N02K	HM180N02K	TO-252-2L	-	-	-

Absolute Maximum Ratings (T_c=25[°]Cunless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	Vds	20	V	
Gate-Source Voltage	Vgs	±12	V	
Drain Current-Continuous	Ι _D	185	А	
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	130	А	
Pulsed Drain Current	I _{DM}	400	А	
Maximum Power Dissipation	PD	130	W	
Derating factor		0.87	W/℃	
Single pulse avalanche energy (Note 5)	E _{AS}	1700	mJ	



HM180N02K

Operating Junction and Storage Temperature Range	T _J ,T _{STG}	-55 To 175	°C

Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 2)	R _{θJC}	1.15	°C /W

Electrical Characteristics (T_c=25°C unless otherwise noted)

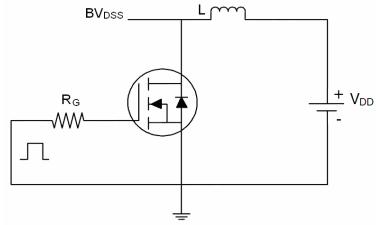
Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	20	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±12V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	·					
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	0.5	0.75	1.2	V
Durain Course On Chata Desintance	P	V _{GS} =4.5V, I _D =20A	-	1.4	2.0	
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =2.5V, I _D =15A		1.6	2.4	mΩ
Forward Transconductance	g fs	V _{DS} =5V,I _D =20A	100	-	-	S
Dynamic Characteristics (Note4)	·					
Input Capacitance	Clss		-	5000	-	PF
Output Capacitance	Coss	V_{DS} =10V, V_{GS} =0V,	-	1200	-	PF
Reverse Transfer Capacitance	Crss	- F=1.0MHz -		900	-	PF
Switching Characteristics (Note 4)	·					
Turn-on Delay Time	t _{d(on)}		-	12	-	nS
Turn-on Rise Time	tr	V_{DD} =10V,I _D =2A,R _L =15 Ω	-	13	-	nS
Turn-Off Delay Time	t _{d(off)}	V _{GS} =10V,R _G =2.5Ω	-	45	-	nS
Turn-Off Fall Time	t _f		-	32	-	nS
Total Gate Charge	Qg	<u>)/ 40)// 004</u>	-	70		nC
Gate-Source Charge	Q _{gs}		-	16		nC
Gate-Drain Charge	Q _{gd}	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$			nC	
Drain-Source Diode Characteristics	·					
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =20A	-		1.2	V
Diode Forward Current (Note 2)	I _S		-	-	150	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 20A	-	49	_	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs ^(Note3)	-	66	_	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negli	gible (turi	n-on is do	minated b	y LS+LD)

Notes:

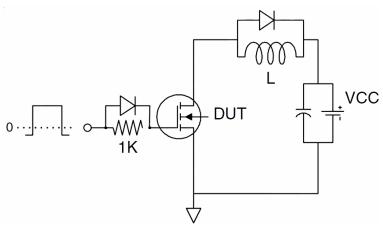
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- **5.** E_{AS} condition : Tj=25 $^{\circ}$ C,V_{DD}=20V,V_G=10V,L=1mH,Rg=25 Ω , I_{AS}=58.5A



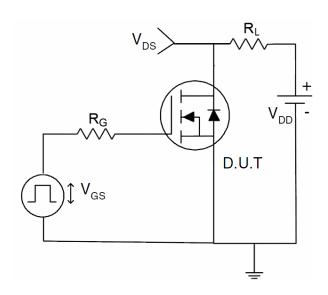
Test circuit 1) E_{AS} Test Circuit



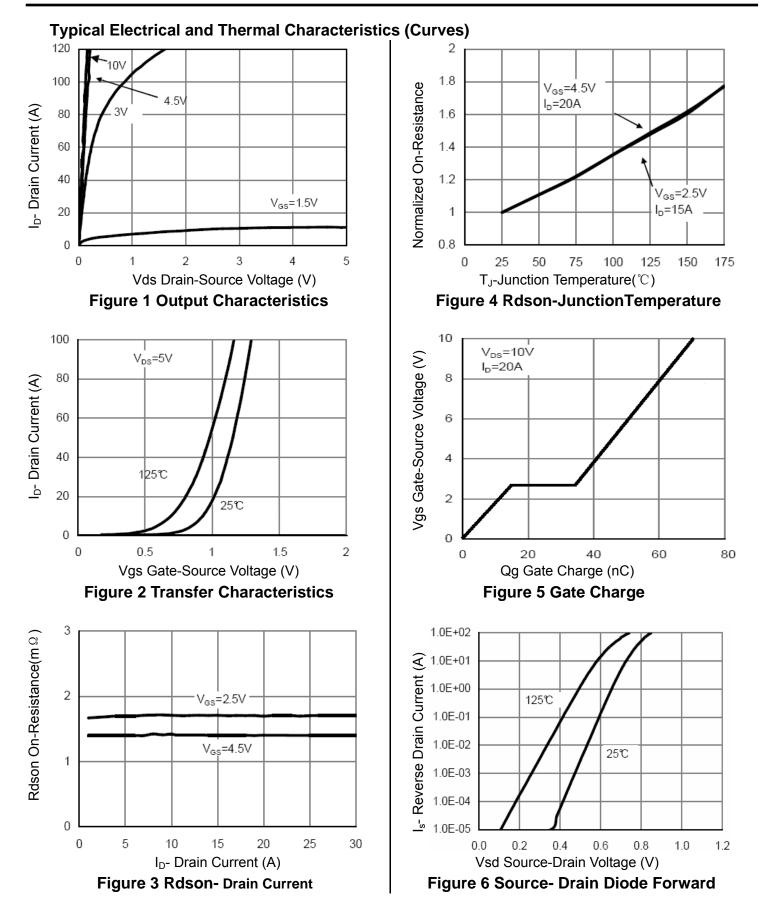
2) Gate Charge Test Circuit



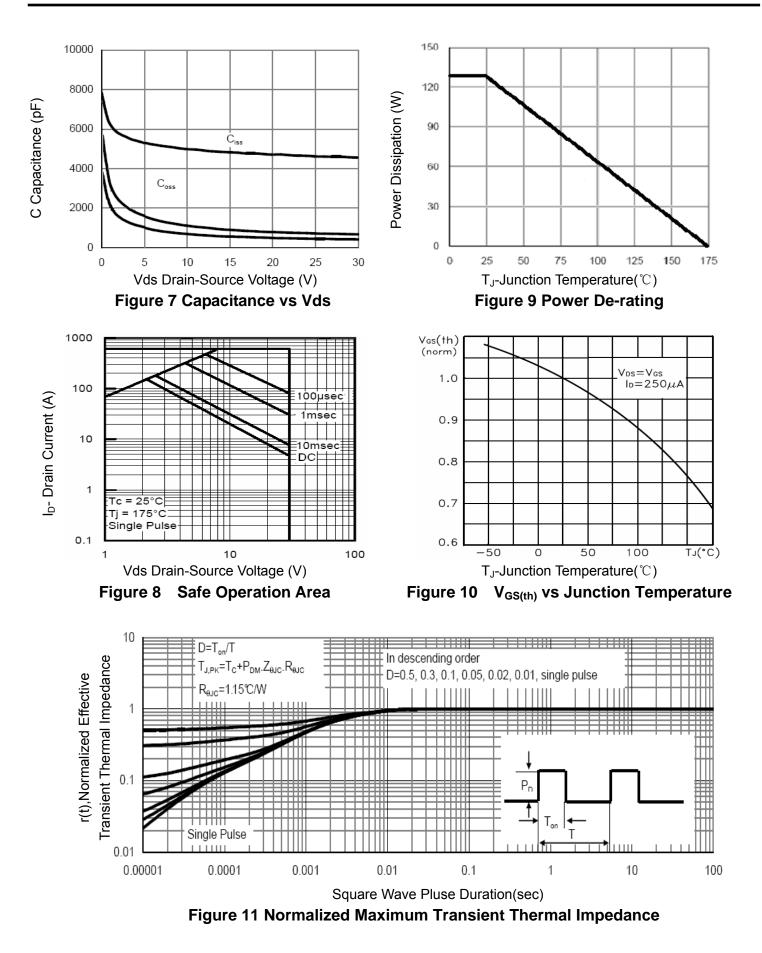
3) Switch Time Test Circuit





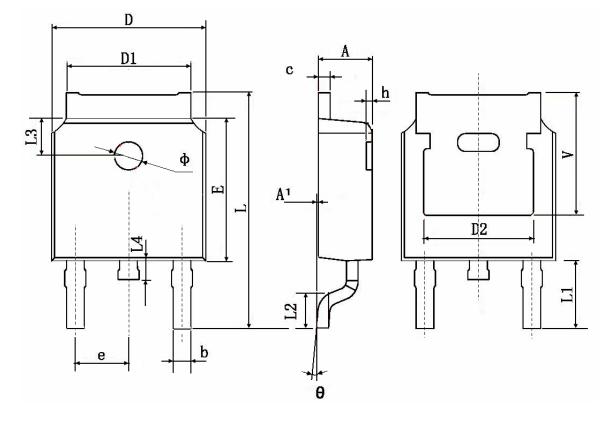








TO-252 Package Information



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min.	Max.	Min.	Max.	
А	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.83	TYP.	0.190) TYP.	
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Φ	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350	TYP.	0.211	TYP.	



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